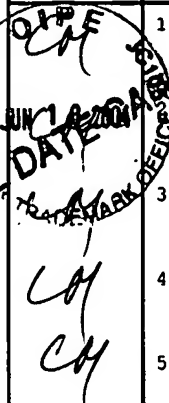
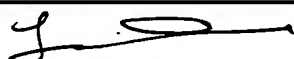


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Substitute for Form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application Number		10/650,059	
		Filing Date		August 27, 2003	
		First Named Inventor		Ryouichi YOKOYAMA et al	
		Group Art Unit		2855	
		Examiner Name			
Sheet	1	of	1	Attorney Docket Number	03506/LH
<b>OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published			T <sup>2</sup>
 CH CH	1	K. TANAKA, K. ISHIHARA and K. INOUE: "A METHOD OF X-RAY STRESS MANAGEMENT FOR CUBIC POLYCRYSTALS WITH FIBER TEXTURE", J. Soc. Mat. Sci., Japan, Vol. 45, No. 8, pages 945-950, August, 1996.			
	3	K. TANAKA, Y. AKINIWA, T. ITO and K. INOUE: "ELASTIC CONSTANTS AND X-RAY STRESS MEASUREMENT OF CUBIC THIN FILMS WITH FIBER TEXTURE", JSME International Journal, Series A, Vol. 42, No. 2, pages 224-234, 1998.			
	4	K. TANAKA and Y. AKINIWA: "X-RAY STRESS MANAGEMENT OF HEXAGONAL POLYCRYSTALS WITH [001] FIBER TEXTURE", JSME International Journal, Series A, Vol. 41, No. 2, pages 287-289, 1998.			
	5	Jikkenbutsurigaku kouza 20, X-sen kaisetsu (Experimental physics course 20, x-ray diffraction), edited by K. Kohra, KYORITSU SHUPPAN CO., LTD., 1998, pages 571-575, "16.2 x-sen ouryokusokuteino genri (Principle of X-ray stress measurement)".			
	5	X-sen kesshoukaisekino tebiki, Ouyoubutsurigaku sensho (Guide to X-ray Crystal Analysis, Applied Physics Sampler), T. Sakurai, Shokabou, 1983, page 53.			
Examiner Signature				Date Considered	11/22/04

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> Place a check here if English translation is attached.

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Substitute for Form 1449A/PTO				Application Number	10/650,059
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Filing Date	August 27, 2003
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				Group Art Unit	2855
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Sheet	1	of	2	Attorney Docket Number	03506/LH
<b>OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials	Cit e No. <sup>1</sup>	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published			T <sup>2</sup>
CM	2	Tanaka et al., "X-ray residual stress measurement of aluminum thin films with 111 fiber texture" Journal of the Society of Materials Science, Japan, Soc. Mater. Sci. Japan, Japan, Vol. 45, No. 10, pages 1138-1144, XP00902646, ISSN: 0514-5163, October 1996.			
CM	3	Lappalainen J. Et al., "Electrical and Mechanical Properties of Ferroelectric Thin Films Laser Ablated from a PBO.97NDO.02 (ZRO.55TI0.45)03 Target" Journal of Applied Physics, American Institute of Physics. New York, US, Vol. 82, No. 7, pages 3469-3477, XP000738070, ISSN: 0021-8979, October 1, 1997.			
Examiner Signature				Date Considered	11/22/04

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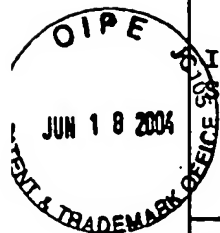
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Sheet	1	of	2	Attorney Docket Number	03506/LH

### U.S. PATENT DOCUMENTS

Exam. Inits <sup>*</sup>	Cite No <sup>1</sup>	Document Number	Kind Code <sup>2</sup>	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion

### FOREIGN PATENT DOCUMENTS

Exam. Inits <sup>*</sup>	Cite No <sup>1</sup>	Offc	Document Number <sup>4</sup>	Kind Code <sup>5</sup>	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T <sup>6</sup>
CM	1	DE	197 19 473	A1	FRAUNHOFER GES FORSCHUNG	04-02-1998		

Examiner Signature		Date Considered	11/22/04
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